

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/659,271	YAGUCHI ET AL.	
Examiner		Art Unit		Page 1 of 1
John L. Goodrow		1756		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,677,093	01-2004	Yoshino et al.	430/106.2
*	B	US-6,130,017	10-2000	Hayashi et al.	430/108.3
*	C	US-2004/0043317	03-2004	Yaguchi et al.	430/108.8
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-319021 11-2001	04-1999	Japan		
	O	JP 2002-129063 5-2002	08-2002	Japan		
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		10/659,271	YAGUCHI ET AL.	
Examiner		Art Unit		Page 1 of 1
John L. Goodrow		1756		

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,677,093	01-2004	Yoshino et al.	430/106.2
*	B	US-6,130,017	10-2000	Hayashi et al.	430/108.3
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2000-319021	11-2000	Japan		
	O	JP 2002-1290683	09-2002	Japan		
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.